Substitute Form PTO-1449
(Modified)

U.S. Department of Commerce Patent and Trademark Office Attorney's Docket No. 07977-024004

Application No.

Information Disclosure Statement
by Applicant
(Use several sheets if necessary)

Applicant

Isamu Kobori et al.

Filing Date

Group Art Unit

Substitute Disclosure Form (PTO-1449)

(37 CFR §1.98(b))

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
KK	AA	5,413,958	05/95	Imahashi, et al.			•
	AB	5,529,630	06/96	Imahashi, et al.			
	AC	5,595,923	01/97	Zhang, et al.			
	AD	5,712,191	1/27/98	Nakajima, et al.			
	AE	5,731,613	3/24/98	Yamazaki, et al.			
	AF	5,767,930	06/98	Kobayashi, et al.			
	AG	5,854,494	05/95	Yamazaki, et al.			
	AH	5,854,096	12/98	Ohtani, et al.		, , , , , , , , , , , , , , , , , , , ,	
	AI	5,937,282	8/10/99	Nakajima, et al.			
	AJ	5,959,313	9/28/99	Yamazaki, et al.			
	AK	5,966,594	10/99	Adachi, et al.		- · · · · · · · · · · · · · · · · ·	
	AL	6,051,453	04/2000	Takemura		-	
KR	AM	6,071,764	06/2000	Zhang, et al.			
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Examiner	Desig.	Document	Publication	Country or			Translation	
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AO	05, 009,089 A	01/1993	Japan				
_	AP	01-222432	09/05/89	Japan			ABS	
	AQ	06-260643	09/16/94	Japan			ABS	
	AR	2-150017	06/08/90	Japan			ABS	
	AS	2-224255	09/06/90	Japan			ABS	
	AT	6-84793	03/25/94	Japan			ABS	
	AU	6-124962	05/06/94	Japan			ABS	
	ΑV							

Other Documents (include Author,	Title, Date, and Place of Publication)
Examiner Signature	Date Considered 2 8 05
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Substitute Form PTO-1449 (Modified)			Application No.	
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(Use several sheets if necessary)		Filing Date	Group Art Unit	
(37 CFR §1.98(b))				

Examiner Initial	Desig. ID	Document
	AW	Y. Fukushima, et al., "A Poly-Si TFT Process for High Speed and Low Voltage CMOS Circuits", Extended Abstracts of the 1993 International Conference on Solid State Devices and Materials, Makuhari, pp. 993-995, 1993.
	AX	

Examiner Signature

Date Considered

28

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